

N-[3,5-Bis(trifluoromethyl)phenyl]salicylaldimine

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Key indicators

Single-crystal X-ray study
 $T = 180\text{ K}$
 Mean $\sigma(\text{C}-\text{C}) = 0.005\text{ \AA}$
 Disorder in main residue
 R factor = 0.063
 wR factor = 0.191
 Data-to-parameter ratio = 9.5

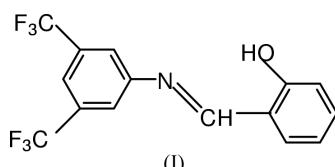
For details of how these key indicators were automatically derived from the article, see <http://journals.iucr.org/e>.

The title compound, $C_{15}H_9F_6NO$, is non-planar with a dihedral angle between the two aromatic rings of $29.57(2)^\circ$. The central $N=C$ bond distance of $1.276(4)\text{ \AA}$ is typical for a double bond. There are intramolecular $O-\text{H}\cdots\text{N}$ and weak intermolecular $C-\text{H}\cdots\text{F}$ hydrogen bonds.

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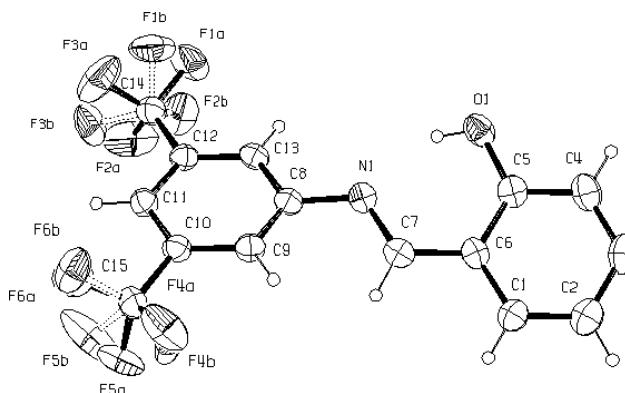
Comment

Solvent extraction is now widely accepted as a process for the recovery of metal ions from aqueous solution in hydro-metallurgical and environmental applications (El Aamrani *et al.*, 1999), with a new interest in the processing of heavy metals by chelation in combination with supercritical fluid (SCF) extraction processing. We have designed novel Schiff base-type chelating agents by attaching CO_2 -philic fluoroalkyl groups, and synthesized and characterized these compounds for supercritical CO_2 extraction of heavy metals. In this study, we report the structure of the title compound, (I).

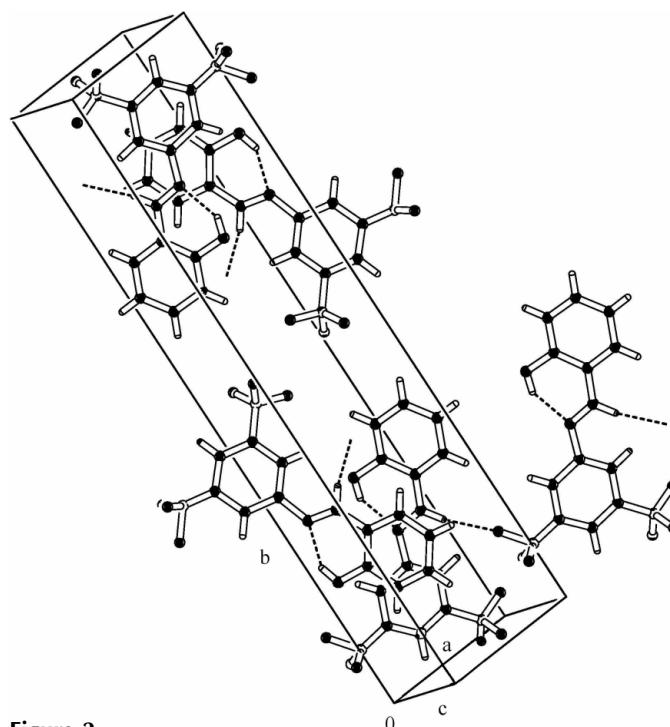


The molecular structure of (I) is shown in Fig. 1. The $\text{C}8-\text{N}1$ and $\text{C}7-\text{C}6$ bond lengths are $1.417(4)$ and $1.439(4)\text{ \AA}$, respectively (Table 1), and agree with the corresponding distances in $2-[(4\text{-hydroxyphenyl})iminomethyl]thiophene$ [$1.422(2)$ and $1.447(3)\text{ \AA}$; Kazak *et al.*, 2000] and *trans*-[4-dimethylaminophenyl]iminomethyl]-*N*-methylpyridinium *para*-toluenesulfonate [$1.413(3)$ and 1.461 \AA ; Coe *et al.*, 2001]. The $\text{N}1=\text{C}7$ bond length of $1.276(4)\text{ \AA}$ is typical of a double bond, similar to the corresponding bond lengths in *N*-(2,4-dinitrophenyl)-*N*-methylhydrazone [$1.279(2)\text{ \AA}$; Aygün *et al.*, 1998], 2-salicylideneamino-4,5,6,7-tetrahydrobenzo[*b*]thiophene-3-carbonitrile [$1.281(2)\text{ \AA}$; Elerman & Elmali, 1998] and $2-[(4\text{-hydroxyphenyl})iminomethyl]thiophene$ [$1.282(2)\text{ \AA}$; Kazak *et al.*, 2000]. The $\text{O}1-\text{C}5$ distance of $1.360(4)\text{ \AA}$ is close to the value of $1.349(6)\text{ \AA}$ in 3-*tert*-butyl-2-hydroxy-5-methoxyazobenzene (İşik *et al.*, 1998). The dihedral angle between the rings formed by atoms $\text{C}1-\text{C}6$ and $\text{C}8-\text{C}13$ is $29.57(2)^\circ$.

There is an intramolecular $\text{O}1-\text{H}1\cdots\text{N}1$ hydrogen bond and a weak intermolecular $\text{C}7-\text{H}7\cdots\text{F}1a^i$ hydrogen bond (Table 2). Both CF_3 groups show rotational disorder.

**Figure 1**

An ORTEPIII (Burnett & Johnson, 1996) drawing of (I), showing the atomic numbering scheme. Displacement ellipsoids for non-H atoms are shown at the 30% probability level. The site-occupancy factors are 0.64 (1) and 0.36 (1) for F1a–F6a and F1b–F6b, respectively.

**Figure 2**

PLATON/PLUTON plot (Spek, 1997), showing part of the hydrogen-bond network and the stacking of molecules. The disordered F atoms with 36% occupancy have been omitted for clarity.

Experimental

An ethanol solution of 3,5-bis(trifluoromethyl)aminobenzene (2.29 g/20 ml ethanol) was added dropwise, at room temperature, to a solution of salicylaldehyde (1.22 g, 0.01 mol) in ethanol (20 ml), and large amounts of a yellow precipitate were formed. The mixture was stirred for 30 min at this temperature and filtered under vacuum. Spectroscopically pure (I) was obtained by crystallization from toluene as pale-yellow needles (yield: 93%, m.p.: 369–371 K); elemental analysis, calculated for $C_{15}H_9F_6N$: C 54.05, H 2.70, N 4.20%; found: C 54.34, H 2.78, N 4.19%. ^1H NMR (CDCl_3 , 400 MHz): δ 6.9–7.1 (m, 7H, Ar–H), 8.5 (s, 1H, H–C≡N), 12.2 (s, 1H, OH). IR (KBr) 3600–3300 (br, Ph–OH), 2950 (H–CN), 1650 (C≡N), 1600

(Ar–CH). UV-vis (CHCl_3): $\lambda = 240$ (ε : 2000), 276 (max., ε : 2927), 346 nm (ε : 1835).

Crystal data

$C_{15}H_9F_6NO$	$D_x = 1.586 \text{ Mg m}^{-3}$
$M_r = 333.23$	Mo $K\alpha$ radiation
Monoclinic, $P2_1/a$	Cell parameters from 35 reflections
$a = 7.509 (1) \text{ \AA}$	$\theta = 5\text{--}25^\circ$
$b = 26.634 (2) \text{ \AA}$	$\mu = 0.16 \text{ mm}^{-1}$
$c = 7.854 (1) \text{ \AA}$	$T = 180 (2) \text{ K}$
$\beta = 117.34 (1)^\circ$	Plate, yellow
$V = 1395.3 (3) \text{ \AA}^3$	$0.30 \times 0.30 \times 0.02 \text{ mm}$
$Z = 4$	

Data collection

Siemens P4 diffractometer	$\theta_{\text{max}} = 25.2^\circ$
ω scans	$h = -4 \rightarrow 9$
Absorption correction: none	$k = -30 \rightarrow 31$
9212 measured reflections	$l = -9 \rightarrow 9$
2508 independent reflections	1 standard reflection
1400 reflections with $I > 2\sigma(I)$	frequency: 120 min
$R_{\text{int}} = 0.068$	intensity decay: none

Refinement

Refinement on F^2	$w = 1/[\sigma^2(F_o^2) + (0.0908P)^2]$
$R[F^2 > 2\sigma(F^2)] = 0.063$	where $P = (F_o^2 + 2F_c^2)/3$
$wR(F^2) = 0.191$	$(\Delta/\sigma)_{\text{max}} = 0.062$
$S = 1.06$	$\Delta\rho_{\text{max}} = 0.22 \text{ e \AA}^{-3}$
2508 reflections	$\Delta\rho_{\text{min}} = -0.23 \text{ e \AA}^{-3}$
264 parameters	Extinction correction: SHELXL97
H-atom parameters constrained	Extinction coefficient: 0.011 (3)

Table 1
Selected geometric parameters (\AA , $^\circ$).

C12–C11	1.375 (4)	N1–C8	1.417 (4)
C12–C13	1.379 (5)	C1–C6	1.381 (4)
O1–C5	1.360 (4)	C6–C7	1.439 (4)
N1–C7	1.276 (4)	C8–C9	1.377 (4)
C11–C12–C13	120.7 (3)	C1–C6–C7	120.8 (3)
C11–C12–C14	120.0 (3)	C5–C6–C7	120.6 (3)
C13–C12–C14	119.3 (3)	N1–C7–C6	123.5 (3)
C7–N1–C8	119.5 (3)	C9–C8–N1	123.6 (3)
O1–C5–C4	117.8 (3)	C13–C8–N1	117.1 (3)

Table 2
Hydrogen-bonding geometry (\AA , $^\circ$).

$D-\text{H}\cdots A$	$D-\text{H}$	$\text{H}\cdots A$	$D\cdots A$	$D-\text{H}\cdots A$
O1–H1 \cdots N1	0.82	1.88	2.604 (4)	147
C7–H7 \cdots F1a ⁱ	0.93	2.48	3.351 (8)	156

Symmetry code: (i) $1+x, y, 1+z$.

The disordered trifluoromethyl F atoms were refined anisotropically, with geometrical and displacement parameter restraints for the two sets of positions; the refined occupancy factors were 0.639 (14) and 0.361 (14).

Data collection: XSCANS (Siemens, 1991); cell refinement: XSCANS; data reduction: SHELXTL (Bruker, 2001); program(s) used to solve structure: SHELXS97 (Sheldrick, 1997); program(s) used to refine structure: SHELXL97 (Sheldrick, 1997); molecular graphics: ORTEPIII (Burnett & Johnson, 1996); software used to prepare material for publication: WinGX (Farrugia, 1999), PARST (Nardelli, 1995) and PLATON (Spek, 1997).

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References

- Aygün, M., Işık, Ş., Öcal, N., Nawaz, T. M., Kaban, Ş. & Büyükgüngör, O. (1998). *Acta Cryst. C*54, 527–529.
- Bruker (2001). *SHELXTL*. Version 6.12. Bruker AXS Inc., Madison, Wisconsin, USA.
- Burnett, M. N. & Johnson, C. K. (1996). *ORTEPIII*. Report ORNL-6895. Oak Ridge National Laboratory, Tennessee, USA.
- Coe, B. J., Harris, J. A., Coles, S. J. & Hursthouse, M. B. (2001). *Acta Cryst. C*57, 857–858.
- El Aamrani, F. Z., Kumar, A., Cortina, J. L. & Sastre, A. M. (1999). *Anal. Chim. Acta*, **382**, 205–231.
- Elerman, Y. & Elmali, A. (1998). *Acta Cryst. C*54, 529–531.
- Farrugia, L. J. (1999). *J. Appl. Cryst.* **32**, 837–838.
- Işık, Ş., Aygün, M., Kocaokutgen, H., Nawaz, T. M., Büyükgüngör, O. & Erdönmez, A. (1998). *Acta Cryst. C*54, 859–860.
- Kazak, C., Aygün, M., Turgut, G., Odabaşolu, M., Özbeş, S. & Büyükgüngör, O. (2000). *Acta Cryst. C*56, 1044–1045.
- Nardelli, M. (1995). *J. Appl. Cryst.* **32**, 563–571.
- Sheldrick, G. M. (1997). *SHELXS97* and *SHELXL97*. University of Göttingen, Germany.
- Siemens (1991). *XSCANS*. Version 2.10b. Siemens Analytical X-ray Instruments Inc., Madison, Wisconsin, USA.
- Spek, A. L. (1997). *PLATON*. Version of May 1997. University of Utrecht, The Netherlands.